

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

6050/54207 (LBE-B-1506)

Application Number

09/608,311

Applicant(s)

XIAO-DONG XIANG et al.


Filing Date

JUNE 30, 2000

Group Art Unit

2429

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	REF	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
PL		5,559,328	09/1996	Weiss et al.	250	306	
		5,619,035	04/1997	Weiss et al.	250	306	
		5,821,410	10/1998	Xiang et al.	73	105	
		5,900,618	05/1999	Anlage et al.	250	201.3	
		6,173,604	01/2001	Xiang et al.	73	105	
							
						TC 2000 10/1/2001	

FOREIGN PATENT DOCUMENTS

	REF	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
							YES	NO
PL		WO 99/16102	04/1999	PCT/US98/19764				
PL		117,656	11/2000	Taiwan (R.O.C.)				✓

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

A1	Synge, E.H., "A SUGGESTED METHOD FOR EXTENDING MICROSCOPIC RESOLUTION INTO THE ULTRA-MICROSCOPIC REGION," Philos Magazine, Vol. 6, 1928, pp. 356-362.
A2	Soochoo, R.F., "A MICROWAVE MAGNETIC MICROSCOPE," Journal of Applied Physics, Vol. 33, No. 3, March, 1962, pp. 1276-1277.

EXAMINER

Paveth

DATE CONSIDERED

11/14/2001

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

6050/54207 (LBI-AB-1506)

Application Number

09/608,311

Applicant(s)

XIAO-DONG XIANG, et al.

Filing Date

JUNE 30, 2000

Group Art Unit

2829

*EXAMINER
INITIAL

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Bryant, C.A., et al., "NONCONTACT TECHNIQUE FOR THE LOCAL MEASUREMENT OF SEMICONDUCTOR RESISTIVITY," The Review of Scientific Instruments, Vol. 36, No. 11, November, 1965, pp. 1614-1617.

Ash, E.A., et al., "SUPER-RESOLUTION APERTURE SCANNING MICROSCOPE," Nature, Vol. 237, 30 June 1972, pp. 510-512.

Gutmann, Ronald J., et al., "MICROWAVE SCANNING MICROSCOPY FOR PLANAR STRUCTURE DIAGNOSTICS," IEEE MTT-S Digest, 1987, pp. 281-284.

Fee, M., et. al., "SCANNING ELECTROMAGNETIC TRANSMISSION LINE MICROSCOPE WITH SUB-WAVELENGTH RESOLUTION," Optics Communications, Vol. 69, No. 3 & 4, 1 January 1989, pp. 219-224.

Xiang, X.-D., et al., "USE OF A HELICAL RESONATOR AS A CAPACITIVE TRANSDUCER IN VIBRATING REED MEASUREMENTS," Rev. Sci. Instrument, Vol. 60, No. 9, September, 1989, pp. 3035-3040.

Pozar, David M., "MICROWAVE ENGINEERING," 1990, Addison-Wesley Publishing Company, Reading, Massachusetts, Chapter 7.1, Microwave Resonators, pp. 336-347, Chapter 7.8, Cavity Perturbations, pp. 371-373.

Tabib-Azar, Massood, et al., "NON-DESTRUCTIVE CHARACTERIZATION OF MATERIALS BY EVANESCENT MICROWAVES," Measuring Science Technology, Vol. 4, 1993, pp. 583-590.

Vlahacos, C.P., et al., "NEAR-FIELD SCANNING MICROWAVE MICROSCOPE WITH 100 MICRON RESOLUTION," Applied Physics Letters, Vol. 69, No. 21, 18 November 1996, pp. 3272-3274.

Lu, Yalin, et al., "NONDESTRUCTIVE IMAGING OF DIELECTRIC-CONSTANT PROFILES AND FERROELECTRIC DOMAINS WITH A SCANNING-TIP MICROWAVE NEAR-FIELD MICROSCOPE," Science, Vol 276, 27 June 1997, pp. 2004-2006.

Gao, Chen, et al., "HIGH SPATIAL RESOLUTION QUANTITATIVE MICROWAVE IMPEDANCE MICROSCOPY BY A SCANNING TIP MICROWAVE NEAR-FIELD MICROSCOPE," Applied Physics Letters, Vol. 71, No. 12, 29 September 1997, pp. 1872-1874.

Wei, T., et al., "SCANNING TIP MICROWAVE NEAR-FIELD MICROSCOPE," Applied Physics Letters, vol. 68, No. 24, 10 June 1996, pp. 1-3.

Gao, Chen, et al., "QUANTITATIVE NONLINEAR DIELECTRIC MICROSCOPY OF PERIODICALLY POLARIZED FERROELECTRIC DOMAINS," Applied Physics Letters, vol. 73, No. 8, 24 August 1998, pp. 1146-1148

EXAMINER

DATE CONSIDERED

11/14/2001

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

INFORMATION DISCLOSURE CITATION

(Use several sheets if necessary)

Docket Number (Optional)

6050/54207 (LBL-1B-1506)

Application Number

09/608,311

Applicant(s)

XIAO-DONG XIANG et al.

Filing Date

JUNE 30, 2000

Group Art Unit

2429

*EXAMINER
INITIAL

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

A15 Gao, Chen, Xiang, X.-D., "QUANTITATIVE MICROWAVE NEAR-FIELD MICROSCOPY OF DIELECTRIC PROPERTIES," Review of Scientific Instruments, vol. 69, No. 11, November, 1998, pp. 3846-3851.

A16 Duewer, Fred, et al., "TIP-SAMPLE DISTANCE FEEDBACK CONTROL IN A SCANNING EVANESCENT MICROWAVE MICROSCOPE," Applied Physics Letters, Vol. 74, No. 18, 3 May 1999, pp. 2696-2698.

A17 Gao, Chen, et al., "QUANTITATIVE MICROWAVE EVANESCENT MICROSCOPY," Applied Physics Letters, Vol. 75, No. 19, 8 November, 1999, pp. 3005-3007, with ERRATA published in Applied Physics Letters, Vol. 76, No. 5, 31 January 2000, pp. 656.



RECEIVED
MAR - 7 2001
TC 2000 MAIL ROOM

EXAMINER

Parekh

DATE CONSIDERED

11/16/2001

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP Section 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.